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PATENT ABSTRACTS OF JAPAN

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(21)Application number : 09-026112 (71)Applicant : DAINIPPON SCREEN MFG CO LTD

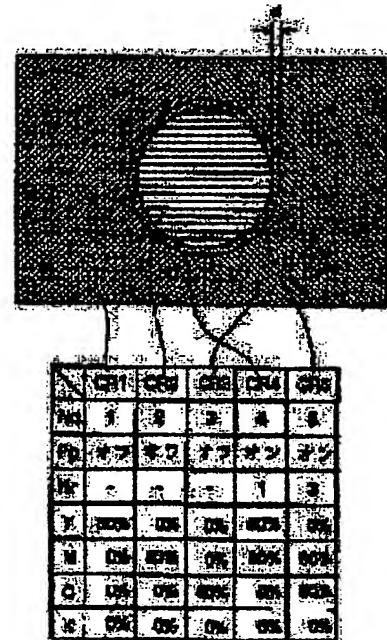
(22)Date of filing : 23.01.1997 (72)Inventor : KITAMURA HIDEAKI

(54) IMAGE MASK PROCESSING DEVICE AND ITS METHOD

(57)Abstract:

PROBLEM TO BE SOLVED: To form a mask area at borders of adjacent image areas through the processing of image data in order to prevent void due to deviated process.

SOLUTION: When the operator selects an image area CR2 being a processing object, processing thickening the processing object area CR2 by a prescribed width (d) is conducted and colors of mask areas CR4, CR5 formed thereby are decided a color of the processing object area CR2 and an original color of the mask areas CR4, CR5. For example, the color of the mask areas is decided by adopting a higher value among color components of the processing object areas and the original color component of the mask areas.



LEGAL STATUS

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